ISSN 0168-583X

Nuclear Instruments & Methods in Physics Research

Editor-in-Chief: Kai Siegbahn

Section B

Beam Interactions with Materials and Atoms

Editors: H. H. Andersen & L. E. Rehn

Master Index
Volumes B42–B50

North-Holland

Scope of NIM-B

Section B of Nuclear Instruments and Methods in Physics Research accepts experimental and theoretical papers of original research covering all aspects of the interaction of energetic beams with atoms, molecules and aggregate forms of matter. This includes ion beam analysis and ion beam modification of materials as well as basic data of importance for these studies.

Topics of general interest include atomic collisions in solids, particle channeling, all aspects of collision cascades, the modification of materials by energetic beams, ion implantation, irradiation-induced changes in materials, the physics and chemistry of beam interactions and the analysis of materials by all forms of energetic radiation. Modification by ion, laser and electron beams for the study of electronic materials, metals, ceramics, insulators, polymers and other important and new material systems are included. Related studies, such as the application of ion beam analysis to biological, archaeological and geological samples, as well as applications to solve problems in planetary science, are also welcome. Energetic beams of interest include atomic and molecular ions, neutrons, positrons and muons, plasmas directed at surfaces, electron and photon beams, including laser treated surfaces and studies of solids by photon radiation from rotating anodes, synchrotrons, etc. In addition, the interaction between various forms of radiation and radiation-induced deposition processes are relevant.

Below are listed keywords to the specialized fields within the scope of the journal.

Basic Data for Materials Modification and Analysis

Range distributions
Stopping powers in gases and solids
X-ray cross sections
Fluorescence yields
Nuclear reaction cross sections
Scattering cross sections

Atomic Collisions in Solids

Atomic and molecular collisions
Collision cascades
Surface interactions
Beam-induced desorption
Beam–foil spectroscopy
Secondary particle emission, sputtering
Channeling
Multiple scattering

Ion Beam Modification of Materials

Ion implantation
Ion beam mixing
Beam-enhanced deposition
Electrical properties of semiconductors
New-phase formation
Optical properties
Defect properties
Friction, wear, erosion
Interfaces, adhesion
Oxidation and corrosion
Superconductivity
Magnetic properties
Other property changes

Radiation Effects

Radiation damage
Particle tracks
Cluster beams
Interaction of plasmas
Laser ablation
Laser and electron-beam induced modification
Energy and radiation transport in matter
High-intensity beams
Other directed energy processes

Analysis of Materials

Ion beam analysis
Ion channeling
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Elastic recoil detection
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Ion-induced nuclear reactions
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Beam optics for analysis and collision studies
Microprobes

Experimental Methods and Equipment

Dosimetry
Target-temperature regulation systems
High-intensity beams
Beam scanning systems
Fitting and interpretation of energy spectra
New experimental methods
New instrumentation concepts

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This volume is printed on acid-free paper

Printed in The Netherlands

Nuclear Instruments and Methods in Physics Research
North-Holland

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Topics of general interest include atomic collisions in solids, particle channeling, all aspects of collision cascades, the modification of materials by energetic beams, ion implantation, irradiation-induced changes in materials, the physics and chemistry of beam interactions and the analysis of materials by all forms of energetic radiation. Modification by ion, laser and electron beams for the study of electronic materials, metals, ceramics, insulators, polymers and other important and new material systems are included. Related studies, such as the application of ion beam analysis to biological, archaeological and geological samples, as well as applications to solve problems in planetary science, are also welcome. Energetic beams of interest include atomic and molecular ions, neutrons, positrons and muons, plasmas directed at surfaces, electron and photon beams, including laser treated surfaces and studies of solids by photon radiation from rotating anodes, synchrotrons, etc. In addition, the interaction between various forms of radiation and radiation-induced deposition processes are relevant.

Below are listed keywords to the specialized fields within the scope of the journal.

Basic Data for Materials Modification and Analysis

Range distributions
Stopping powers in gases and solids
X-ray cross sections
Fluorescence yields
Nuclear reaction cross sections
Scattering cross sections

Atomic Collisions in Solids

Atomic and molecular collisions
Collision cascades
Surface interactions
Beam-induced desorption
Beam–foil spectroscopy
Secondary particle emission, sputtering
Channeling
Multiple scattering

Ion Beam Modification of Materials

Ion implantation
Ion beam mixing
Beam-enhanced deposition
Electrical properties of semiconductors
New-phase formation
Optical properties
Defect properties
Friction, wear, erosion
Interfaces, adhesion
Oxidation and corrosion
Superconductivity
Magnetic properties
Other property changes

Radiation Effects

Radiation damage
Particle tracks
Cluster beams
Interaction of plasmas
Laser ablation
Laser and electron-beam induced modification
Energy and radiation transport in matter
High-intensity beams
Other directed energy processes

Analysis of Materials

Ion beam analysis
Ion channeling
Ion backscattering
Elastic recoil detection
Ion-induced X-rays
Ion-induced nuclear reactions
Low energy ion beam analysis
Secondary ion mass spectrometry
Secondary electron spectroscopy
Neutron scattering
Slow positron beams
Subatomic particles analyses
Mössbauer spectroscopy
Photon beams
X-ray techniques
Accelerator mass spectrometry
Nuclear dating techniques

Ion Sources and Beam Optics

Sputter sources
ECR sources
Microbean sources
Other ion sources
Beam optics for analysis and collision studies
Microprobes

Experimental Methods and Equipment

Dosimetry
Target-temperature regulation systems
High-intensity beams
Beam scanning systems
Fitting and interpretation of energy spectra
New experimental methods
New instrumentation concepts

Nuclear Instruments & Methods in Physics Research

Editor-in-Chief: Kai Siegbahn

Section B

Beam Interactions with Materials and Atoms

Master Index
Volumes B51 – B60

Editors: H. H. Andersen & L. E. Rehn

North-Holland

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This volume is printed on acid-free paper

Printed in The Netherlands

Nuclear Instruments and Methods in Physics Research
North-Holland

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High Temperature Structural Silicides

Proceedings of the 1st Workshop, Gaithersburg, MD, USA, 2-6 November, 1991

edited by **A.K. Vasudevan** *and* **J.J. Petrovic**

Reprinted from Materials Science and Engineering, A155, Nos. 1,2

The aim of this volume is two-fold. Firstly, to give a current overview on silicide-based structural materials and identify important and promising future research directions. Secondly, it is intended to serve as a catalyst for the expansion of research and development activities in this new field, promoting rapid technology transfer to private industry.

Elevated temperature structural materials represent a key enabling technology for many aspects of advanced aerospace, automotive, energy and environmental systems. High temperature structural silicides constitute an important new class of such materials. Central aspects for the development of structural silicides are improvements in both high and low temperature mechanical properties, with retention of oxidation resistance. Recent composite and alloying approaches have demonstrated significant success in addressing these issues. The optimum development of structural silicides requires the combined efforts of both ceramists and metallurgists owing to their mixed metallic - covalent - ionic atomic bonding state. The contents of this volume will be of interest to both the metallurgical and ceramics communities.

Abbreviated contents: **Silicide Materials.** A comparative overview of molybdenum disilicide composites *(A.K. Vasudevan, J.J. Petrovic)*. Development of continuous fibre reinforced $MoSi_2$ base composites *(M.J. Maloney, R.J. Hecht)*. Application of ternary phase diagrams to the development of $MoSi_2$ based materials *(W.J. Boettinger et al.)*. Appraisal of other silicides as structural materials *(D.M. Shah et al.)*. Processing and properties of Nb_5Si_3 and tough Nb_5Si_3 / Nb laminates *(J. Kajuch et al.)*. Engineering limitations of $MoSi_2$ coatings *(T.A. Kircher, E.L. Courtright)*. **Processing.** Synthesis of molybdenum disilicide by mechanical alloying *(R.B. Schwarz et al.)*. Fabrication, structure and properties of $MoSi_2$ base composites *(D.E. Alman et al.)*. Synthesis of a $MoSi_2$ SiC composite in situ using a solid state displacement reaction *(C.H. Henager et al.)*. Synthesis of $MoSi_2$ single crystals *(T.A. Lograsso)*. **Relationship Between Processing and Mechanical Properties.** Strengthening of discontinuously reinforced $MoSi_2$ composites at high temperatures *(R.M. Aikin, Jr.)*. Interfacial modification in Nb/$MoSi_2$ composites and its effects on fracture toughness *(L. Xiao, R. Abbaschian)*. Effects of carbon additions on high temperature mechanical properties of molybdenum disilicide *(S.A. Maloy et al.)*. **Oxidation.** Oxidation of $MoSi_2$ and comparison with other silicide materials *(D.A. Berztiss et al.)*. Oxidation of $MoSi_2$ based composites *(J. Cook et al.)*. **Creep.** Tensile creep of silicide composites *(S.M. Wiederhorn et al.)*. Creep of molybdenum disilicide composites *(K. Sadananda et al.)*. **Micromechanics.** Dislocations, twins, grain boundaries and precipitates in $MoSi_2$ *(T.E. Mitchell et al.)*. ZrO_2 and ZrO_2 SiC particle reinforced $MoSi_2$ matrix composites *(J.J. Petrovic et al.)*. Modeling of transformation toughening in brittle materials *(R. LeSar et al.)*. Author index. Subject index.

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Prof. H.H. Andersen
Physics Laboratory, H.C. Ørsted Institute
Universitetsparken 5, DK-2100 Copenhagen Ø
Denmark
Tel. +45 35320482 FAX: +45 35320460

Dr. L.E. Rehn
Materials Science Division, Bldg. 223, RM S231
Argonne National Laboratory, 9700 South Cass Ave
Argonne IL 60439, USA
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[3] H. Yamazaki, Proc. 6th Int. Conf. on Ion Beam Modification of Materials, Nucl. Instr. and Meth. B39 (1989) 433.
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1992 660 pages
Price: US$ 257.00 / Dfl. 450.00
ISBN 0-444-89611-2

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The Netherlands
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ELSEVIER
SCIENCE PUBLISHERS

0168-583X(1993)51/60;1-9

ISSN 0168-583X

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Editor-in-Chief: Kai Siegbahn

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Editors: H. H. Andersen & L. E. Rehn

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Prof. H.H. Andersen
The Niels Bohr Institute, Ørsted Laboratory
Universitetsparken 5, DK-2100 Copenhagen Ø
Denmark
Tel. +45 35320482 FAX: +45 35320460

Dr. L.E. Rehn
Materials Science Division, Bldg. 223, RM S231
Argonne National Laboratory, 9700 South Cass Ave
Argonne IL 60439, USA
Tel. +1 708 2529297 FAX: +1 708 2523308

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Composite Materials Series, Volume 8

©1993 790 pages Hardbound Price: Dfl. 520.00 (US $ 297.25) ISBN 0-444-89079-3

Much research has been carried out and a lot of progress has been made towards the use of composite materials in a wide field of tribological applications. In recent years studies have been made to determine to what degree phenomena governing the tribological performance of composites can be generalized and to consolidate interdisciplinary information for polymer-, metal- and ceramic matrix composites. The importance of promoting better knowledge in the areas of friction, lubrication and wear, in general, is demonstrated by the contents of this volume. It covers a wide range of subjects extending from fundamental research on the tribological characteristics of various multi-phase materials up to final applications of composites in wear loaded, technical components. Besides the emphasis on composites tribology, the great practical aspect of the field in many industrial applications is also reviewed by authors who are engaged in applied research as well as those in more academic activities. The articles in this volume will facilitate both researchers and mechanical designers in their work towards a set of predictive, materials engineering-related models for a more reliable use of composites as tribo-materials.
Through the study of, and observation of, the tribology of sensibly formulated composite systems may emerge a clear and more profound understanding of the subject of tribology. In this sense, this book offers a major and critical evaluation of the state of understanding of the principles of tribology and its ability to serve the practical and commercial needs of this technology generally, and particularly in the context of composite systems.

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415/b/597

0168-583X(1994)B61/B70;1-B